

Description

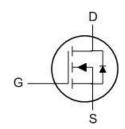
The NTHL095N65S3HF use super junction technology and design to provide excellent RDS(ON) with low gate charge. This super junction MOSFET fits the industry's AC-DC SMPS requirements for PFC, AC/DC power conversion, and industrial power applications.

The NTHL095N65S3HF meet the RoHS and Green Product requirement, 100% EAS guaranteed with full function reliability approved.

TO-247

Features

- · Super Low Gate Charge
- · 100% EAS Guaranteed
- · Green Device Available
- · Excellent CdV/dt effect decline
- · Advanced trench gate super junction technology



Ordering Part Number	Package	Qty(PCS)
NTHL095N65S3HF	TO-247	30





Maximum Ratings ($T_C = 25$ °C unless otherwise specifed)

Symbol	Parameter	Rating	Units
Vos	Drain-Source Voltage	650	V
Vgs	Gate-Source Voltage	±30	V
I _D @T _C =25°C	Continuous Drain Current, V _{GS} @ 10V ^{1,6}	40	А
I _D @T _C =100°C	Continuous Drain Current, V _{GS} @ 10V ^{1,6}	29	А
Ірм	Pulsed Drain Current ²	160	А
EAS	Single Pulse Avalanche Energy ³	750	mJ
las	Avalanche Current		А
P _D @T _C =25°C	Total Power Dissipation ⁴	470	W
Тѕтс	Storage Temperature Range	-55 to 150	°C
TJ	Operating Junction Temperature Range	-55 to 150	°C
R ₀ JA	Thermal Resistance Junction-ambient ¹	41	°C/W
R _θ JC	Thermal Resistance Junction-Case ¹	0.27	°C/W



Electrical Characteristics (at Tj = 25 °C, unless otherwise specified)

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
BV _{DSS}	Drain-Source Breakdown Voltage	V _{GS} =0V , I _D =250uA	650			V
$\triangleBV_{DSS}/\triangleT_J$	BV _{DSS} Temperature Coefficient	Reference to 25°C , I _D =1mA				V/°C
R _{DS(ON)}	Static Drain-Source On-Resistance ²	V _{GS} =10V , I _D =21.5A		75	90	mΩ
		V _{GS} =4.5V , I _D =21.5A				
V _{GS(th)}	Gate Threshold Voltage	V _{GS} =V _{DS} , I _D =250uA	3.2		4.5	V
$\Delta V_{GS(th)}$	GS(th) Temperature Coefficient					mV/°C
I _{DSS}	Drain Course Leakers Current	V _{DS} =650V , V _{GS} =0V , T _J =25°C			5	uA
	Drain-Source Leakage Current	V _{DS} =650V, V _{GS} =0V , T _J =150°C		1000		
I _{GSS}	Gate-Source Leakage Current	V _{GS} =±30V , V _{DS} =0V			±100	nA
gfs	Forward Transconductance	V _{DS} =20V , I _D =21.5A		30		S
R _g	Gate Resistance	V _{DS} =0V , V _{GS} =0V , f=1MHz		1		Ω
Qg	Total Gate Charge	V _{DS} =480V , V _{GS} =10V , I _D =21.5A		84		
Q _{gs}	Gate-Source Charge			28		nC
Q_{gd}	Gate-Drain Charge			36		
T _{d(on)}	Turn-On Delay Time	VGS=10V, VDS=400V, RG=27Ω, ID=21.5A		89		
Tr	Rise Time			131		ns
T _{d(off)}	Turn-Off Delay Time			204		
T _f	Fall Time			69		
C _{iss}	Input Capacitance	V _{DS} =100V , V _{GS} =0V , f=1MHz		3445		
Coss	Output Capacitance			134		pF
C _{rss}	Reverse Transfer Capacitance			0.6		

Diode Characteristics

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
ls	Continuous Source Current ^{1,4}	V _G =V _D =0V , Force Current			40	Α
VsD	Diode Forward Voltage ²	V _{GS} =0V , I _S =21.5A , T _J =25°C	0.7	0.9	1.1	V
t _{rr}	Reverse Recovery Time	IF=21.5 , di/dt=100A/μs ,		113	-	nS
Qrr	Reverse Recovery Charge	T _J = 25°C		0.6		nC

Note:

FÈThe Ádata Ádested Áby Ásurface Ánounted Ábn Áa Át Ánch^{2 Á}FR-4 Áboard Ávith Á2OZ Ácopper.

CEThe Ádata Ádested Áby Ápulsed Á Ápulse Ávidth Ág 300 us Á Áduty Ádycle Ág 2%

HÈ he EAS data shows Max. rating . The test condition is VRÁVÁGÍ »Ô,VDD=200V,VGS=10V,L=30mH I È heÁpowerÁdissipationÁsÁimitedÁbyÁ150°C junctionÁemperature

Í È he Áslata Ás Ás heoretically Ás he Ásame Ás sÁ_{D. Á}and Á_{D. Ás} háteal Ás pplications Ás hould Áse Áimited Ásy Ástal Ásower Á dissipation.



Typical Performance Characteristics

Fig 1. Output Characteristics (T_i=25℃)

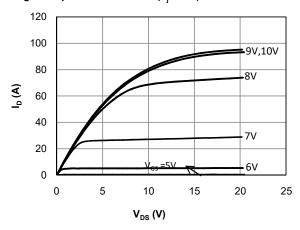


Fig 2. Output Characteristics (T_i =150 $^{\circ}$ C)

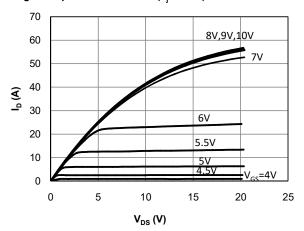


Fig 3: Transfer Characteristics

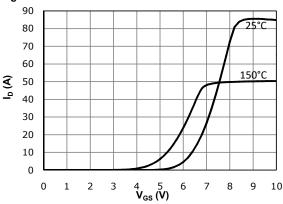


Fig 4: V_{TH} vs. T_j Temperature Characteristics

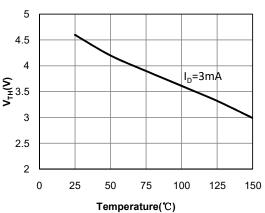


Fig 5: $R_{DS(on)}$ vs. I_{DS} Characteristics(T_j =25 $^{\circ}$ C)

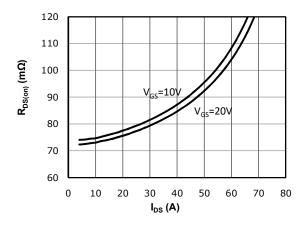


Fig 6: R_{DS(on)} vs. Temperature

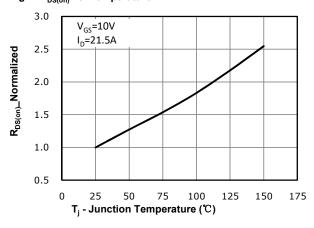




Fig 7: $\mathrm{BV}_{\mathrm{DSS}}$ vs. Temperature 1.08 1.06 1.04 BV_{DSS} (Nomalized) 1.02 1.00 0.98 0.96 0.94 0.92 100 -25 0 25 50 75

T_i - Junction Temperature (℃)

125

Fig 8: R_{DS(on)} vs. Gate Voltage 500 450 $I_{D} = 21.5A$ 400 350 (m) 300 250 150°C 200 150 100 25°C 50 0 5 8 10 6 9 $V_{GS}(V)$

Fig 9: Body-diode Forward Characteristics

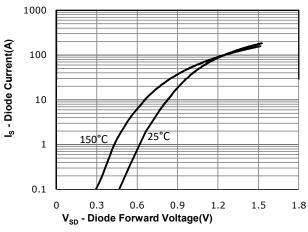


Fig 10: Gate Charge Characteristics

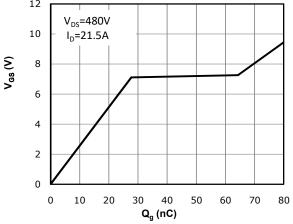


Fig 11: Capacitance Characteristics

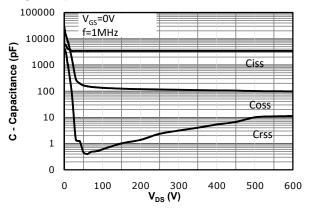
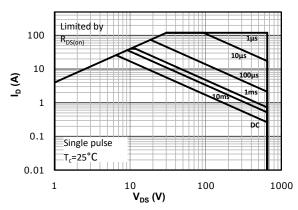
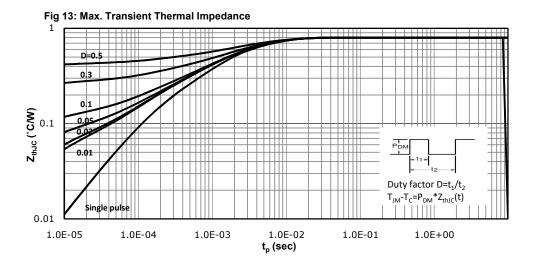


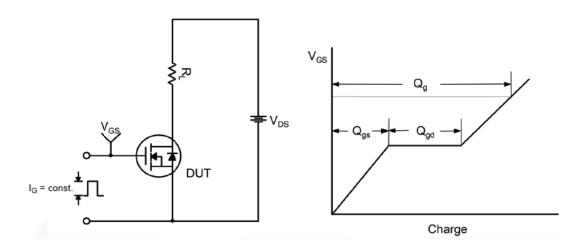
Fig 12: Safe Operating Area



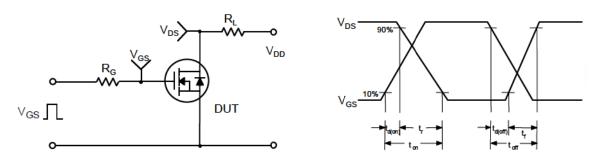


Test Circuit Schematic

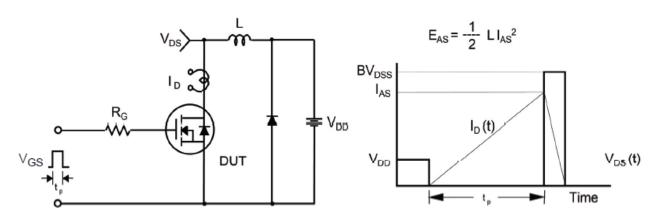
Gate Charge Test Circuit & Waveform



Switching Test Circuit & Waveforms



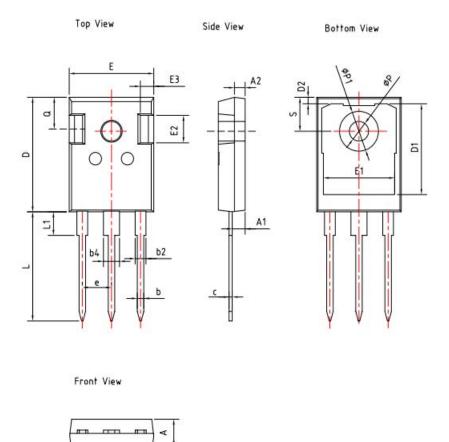
Unclamped Inductive Switching Test Circuit & Waveforms

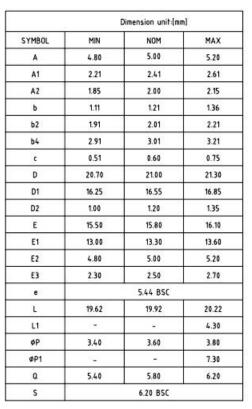




Package Dimensions

Package TO-247





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